Erratum: Nanocalorimetric studies of size effects in magnetic oxides and formation kinetics in silicides

Modifications appear highlighted in bold.

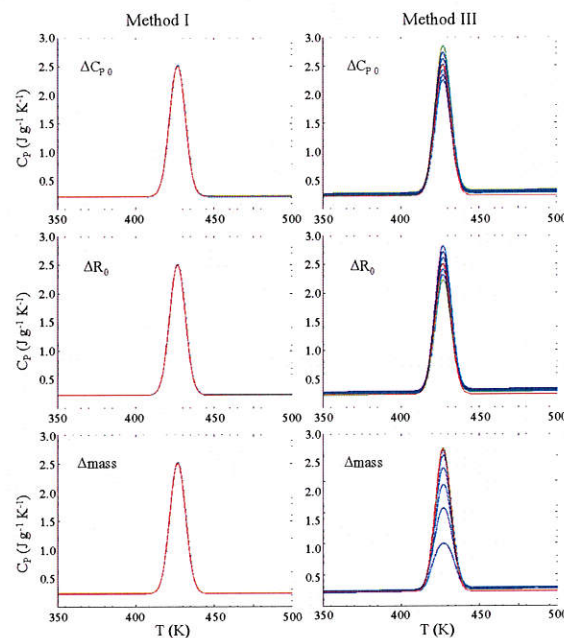- *Chapter 3, page 59, Figure 3.8, figure legend removed and figure caption modified*:

FIG. 3.8 Specific heat capacity simulation by a 0D model realized with Matlab for thin films of In heated from RT up to 500 K. Graphs on the left present the results obtained with method I, while graphs on the right present the results for method III. **Different rows present the results obtained modifying initial differences on heat capacity, resistance, and mass between CCs. The differences on heat capacity and resistance for the SCC are 0.94, 0.96, 0.98, 1.00, 1.02, 1.04 and 1.06 of the RCC values (1 μJ K^{-1} and 30 Ω at room temperature, respectively). In both cases sample thickness is 1 nm. The differences on mass between SCC and RCC are achieved simulating indium samples with 1, 2, 4, 10, 20, 40, and 100 nm thick (in this case, there are no differences in heat capacity or resistance between CCs). Curves show the non-differential signal (red line), and simulation results for both methods (green line corresponds to the first simulation, 0.94 and 1 nm, while blue lines shows subsequent simulations in increasing order).** The 0D model does not contain noise parameters.